Welcome United States Patent and Trademark Office

BROWSE   SEARCH   IEEE XPLORE GUIDE   SUPPORT

IEEE Xplore®
RELEASE 2.4

▨▨Search Session History

Edit an existing query or compose a
new query in the Search Query
Display.

Mon, 3 Sep 2007, 4:08:59 PM EST

Search Query Display

Select a search number (#) to:

- Add a query to the Search Query
  Display
- Combine search queries using
  AND, OR, or NOT

Recent Search Queries

Results

- Delete a search

- Run a search

| #1 | (resetting flip-flops<and>transition time between normal mode and test mode)<and>scan mode signal | 0 |

Indexed by
▨ Inspec®

Help   Contact Us   Privacy & Security   IEEE.org

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L3	0	(714/726.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L4	0	(714/727.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L5	0	(714/730.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:00
L6	0	(714/733.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L7	0	(714/724.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L8	0	(714/42.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:01
L9	0	(714/25.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:13

EAST Search History

L10	0	((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/03 16:03
L11	0	(327/156.ccls.) and ((integrated adj circuit) with normal with test$3 with scan$4) and (reset$4 with flip-flops with (transition adj time) with between with (test adj mode) with (normal adj mode) with (scan adj mode adj signal))	US-PGPUB; USPAT; USOCR	OR	OFF	2007/09/03 16:13